Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... –65°C to +150°C

Ambient Temperature with Power Applied..... –55°C to +125°C

Supply Voltage on V_{CC} to Relative GND[2].....–0.5V to +4.6V

DC Voltage Applied to Outputs[2] in High Z State .....–0.5V to V_{CC} + 0.5V

DC Input Voltage[2] ..... –0.5V to V_{CC} + 0.5V

Current into Outputs (LOW) ..... 20 mA

Operating Range

Range	Ambient Temperature	V_{CC}
Commercial	0°C to +70°C	3.3V ± 0.3V
Industrial	–40°C to +85°C	

DC Electrical Characteristics Over the Operating Range

Parameter	Description	Test Conditions			-12		-15		-17		Unit
					Min.	Max.	Min.	Max.	Min.	Max.	
V_{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = –4.0 mA			2.4		2.4		2.4		V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL} = 8.0 mA				0.4		0.4		0.4	V
V_{IH}	Input HIGH Voltage				2.2	V_{CC} + 0.5	2.2	V_{CC} + 0.5	2.2	V_{CC} + 0.5	V
V_{IL}	Input LOW Voltage[2]				–0.5	0.8	–0.5	0.8	–0.5	0.8	V
I_{IX}	Input Load Current	GND ≤ V_I ≤ V_{CC}			–1	+1	–1	+1	–1	+1	µA
I_{OZ}	Output Leakage Current	GND ≤ V_{OUT} ≤ V_{CC}, Output Disabled			–1	+1	–1	+1	–1	+1	µA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., f = f_{MAX} = $1/t_{RC}$	Comm'l			200		180		170	mA
			Ind'l			220		200		180	mA
I_{SB1}	Automatic CE Power-Down Current —TTL Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH} V_{IN} ≥ V_{IH} or V_{IN} ≤ V_{IL}, f = f_{MAX}				30		30		30	mA
I_{SB2}	Automatic CE Power-Down Current —CMOS Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{CC} – 0.3V, V_{IN} ≥ V_{CC} – 0.3V, or V_{IN} ≤ 0.3V, f = 0	Com'l/Ind'l			8		8		8	mA
			Com'l	L		0.5		0.5		0.5	mA

Note:

2. V_{IL} (min.) = –2.0V for pulse durations of less than 20 ns.

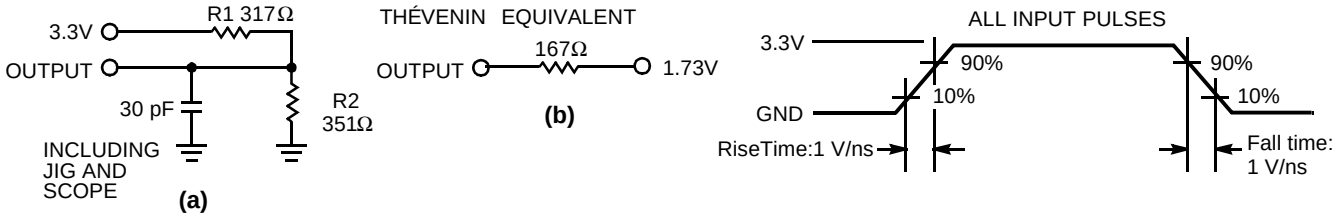
DC Electrical Characteristics Over the Operating Range (continued)

Parameter	Description	Test Conditions			-20 Min.	-20 Max.	-25 Min.	-25 Max.	Unit
V_{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH} = –4.0 mA			2.4		2.4		V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL} = 8.0 mA				0.4		0.4	V
V_{IH}	Input HIGH Voltage				2.2	V_{CC} + 0.5	2.2	V_{CC} + 0.5	V
V_{IL}	Input LOW Voltage[2]				–0.5	0.8	–0.5	0.8	V
I_{IX}	Input Load Current	GND ≤ V_I ≤ V_{CC}			–1	+1	–1	+1	µA
I_{OZ}	Output Leakage Current	GND ≤ V_{OUT} ≤ V_{CC}, Output Disabled			–1	+1	–1	+1	µA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., f = f_{MAX} = $1/t_{RC}$	Com'l			160		150	mA
			Ind'l			170		170	mA
I_{SB1}	Automatic CE Power-Down Current —TTL Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH} V_{IN} ≥ V_{IH} or V_{IN} ≤ V_{IL}, f = f_{MAX}				30		30	mA
I_{SB2}	Automatic CE Power-Down Current —CMOS Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{CC} – 0.3V, V_{IN} ≥ V_{CC} – 0.3V, or V_{IN} ≤ 0.3V, f = 0	Com'l/Ind'l			8		8	mA
			Com'l	L		0.5		0.5	mA

Capacitance[3]

Parameter	Description	Test Conditions	Max.	Unit
C_{IN}	Input Capacitance	T_A = 25°C, f = 1 MHz, V_{CC} = 3.3V	8	pF
C_{OUT}	I/O Capacitance		8	pF

AC Test Loads and Waveforms



Note:
3. Tested initially and after any design or process changes that may affect these parameters.

AC Switching Characteristics[4] Over the Operating Range

Parameter	Description	-12		-15		-17		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Read Cycle								
t_{power}	V_{CC}(typical) to the First Access[5]	1		1		1		µs
t_{RC}	Read Cycle Time	12		15		17		ns
t_{AA}	Address to Data Valid		12		15		17	ns
t_{OHA}	Data Hold from Address Change	3		3		3		ns
t_{ACE}	$\overline{CE}$ LOW to Data Valid		12		15		17	ns
t_{DOE}	$\overline{OE}$ LOW to Data Valid		6		7		8	ns
t_{LZOE}	$\overline{OE}$ LOW to Low Z	0		0		0		ns
t_{HZOE}	$\overline{OE}$ HIGH to High Z[6, 7]		6		7		8	ns
t_{LZCE}	$\overline{CE}$ LOW to Low Z[7]	3		3		3		ns
t_{HZCE}	$\overline{CE}$ HIGH to High Z[6, 7]		6		7		8	ns
t_{PU}	$\overline{CE}$ LOW to Power-Up	0		0		0		ns
t_{PD}	$\overline{CE}$ HIGH to Power-Down		12		15		17	ns
Write Cycle[8, 9]								
t_{WC}	Write Cycle Time	12		15		17		ns
t_{SCE}	$\overline{CE}$ LOW to Write End	10		12		13		ns
t_{AW}	Address Set-Up to Write End	10		12		13		ns
t_{HA}	Address Hold from Write End	0		0		0		ns
t_{SA}	Address Set-Up to Write Start	0		0		0		ns
t_{PWE}	$\overline{WE}$ Pulse Width	10		12		13		ns
t_{SD}	Data Set-Up to Write End	7		8		9		ns
t_{HD}	Data Hold from Write End	0		0		0		ns
t_{LZWE}	$\overline{WE}$ HIGH to Low Z[7]	3		3		3		ns
t_{HZWE}	$\overline{WE}$ LOW to High Z[6, 7]		6		7		8	ns

Notes:

4. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
5. This part has a voltage regulator which steps down the voltage from 5V to 3.3V internally. T_{power} time has to be provided initially before a read/write operation is started.
6. t_{HZOE}, t_{HZCE}, and t_{HZWE} are specified with a load capacitance of 5 pF as in part (b) of AC Test Loads. Transition is measured ± 500 mV from steady-state voltage.
7. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} is less than t_{LZWE} for any given device.
8. The internal write time of the memory is defined by the overlap of $\overline{CE}$ LOW, and $\overline{WE}$ LOW. $\overline{CE}$ and $\overline{WE}$ must be LOW to initiate a write, and the transition of either of these signals can terminate the write. The input data set-up and hold timing should be referenced to the leading edge of the signal that terminates the write.
9. The minimum write cycle time for Write Cycle No. 3 ($\overline{WE}$ controlled, $\overline{OE}$ LOW) is the sum of t_{HZWE} and t_{SD}.

AC Switching Characteristics[4] Over the Operating Range (continued)

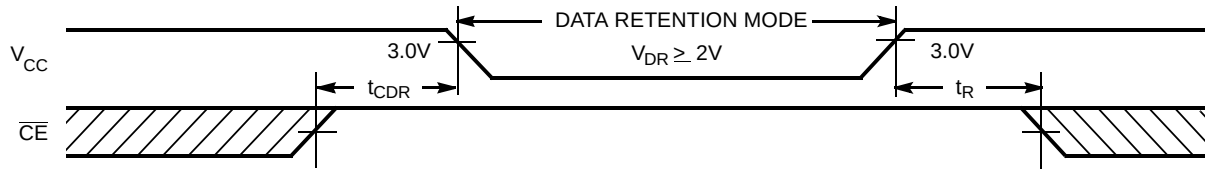
Parameter	Description	-20		-25		Unit
		Min.	Max.	Min.	Max.	
Read Cycle						
t_{power}	V_{CC}(typical) to the First Access[6]	1		1		µs
t_{RC}	Read Cycle Time	20		25		ns
t_{AA}	Address to Data Valid		20		25	ns
t_{OHA}	Data Hold from Address Change	3		3		ns
t_{ACE}	$\overline{CE}$ LOW to Data Valid		20		25	ns
t_{DOE}	$\overline{OE}$ LOW to Data Valid		8		10	ns
t_{LZOE}	$\overline{OE}$ LOW to Low Z	0		0		ns
t_{HZOE}	$\overline{OE}$ HIGH to High Z[6, 7]		8		10	ns
t_{LZCE}	$\overline{CE}$ LOW to Low Z[7]	3		3		ns
t_{HZCE}	$\overline{CE}$ HIGH to High Z[6, 7]		8		10	ns
t_{PU}	$\overline{CE}$ LOW to Power-Up	0		0		ns
t_{PD}	$\overline{CE}$ HIGH to Power-Down		20		25	ns
Write Cycle[9]						
t_{WC}	Write Cycle Time	20		25		ns
t_{SCE}	$\overline{CE}$ LOW to Write End	13		15		ns
t_{AW}	Address Set-Up to Write End	13		15		ns
t_{HA}	Address Hold from Write End	0		0		ns
t_{SA}	Address Set-Up to Write Start	0		0		ns
t_{PWE}	$\overline{WE}$ Pulse Width	13		15		ns
t_{SD}	Data Set-Up to Write End	9		10		ns
t_{HD}	Data Hold from Write End	0		0		ns
t_{LZWE}	$\overline{WE}$ HIGH to Low Z[7]	3		3		ns
t_{HZWE}	$\overline{WE}$ LOW to High Z[6, 7]		8		10	ns

Data Retention Characteristics Over the Operating Range (For L version only)

Parameter	Description	Conditions[10]	Min.	Max	Unit
V_{DR}	V_{CC} for Data Retention		2.0		V
I_{CCDR}	Data Retention Current	$V_{CC} = V_{DR} = 2.0V$, $\overline{CE} \geq V_{CC} - 0.3V$ $V_{IN} \geq V_{CC} - 0.3V$ or $V_{IN} \leq 0.3V$		330	µA
t_{CDR}[3]	Chip Deselect to Data Retention Time		0		ns
t_R[11]	Operation Recovery Time		t_{RC}		ns

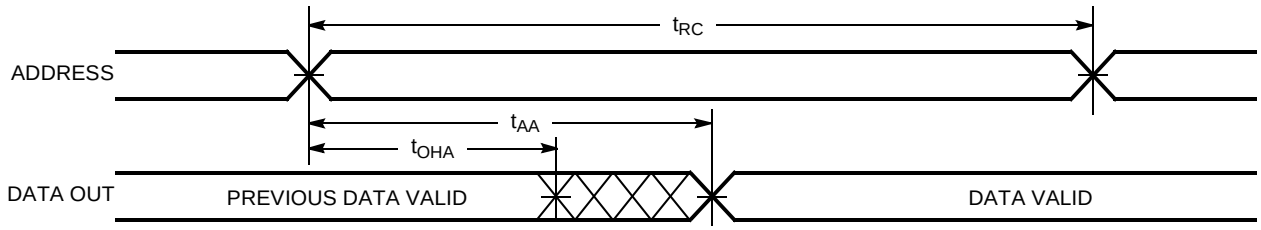
Notes:
10. No input may exceed V_{CC} + 0.5V
11. .$t_r \leq 3$ ns for the -12 and -15 speeds. $t_r \leq 5$ ns for the -20 ns and slower speeds.

Data Retention Waveform

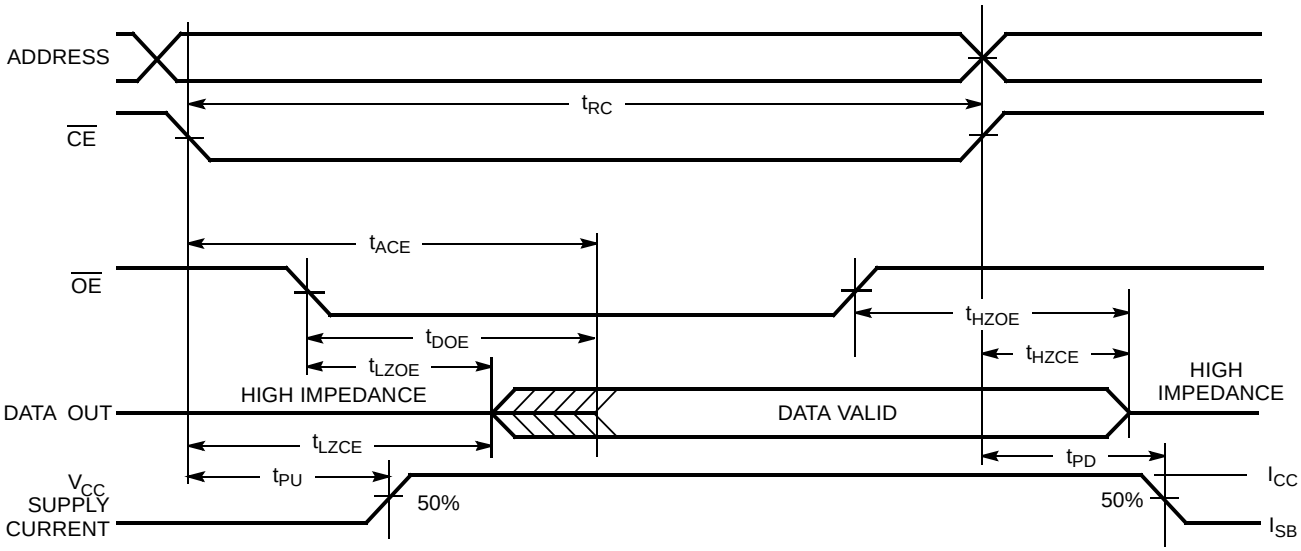


Switching Waveforms

Read Cycle No. 1[12, 13]



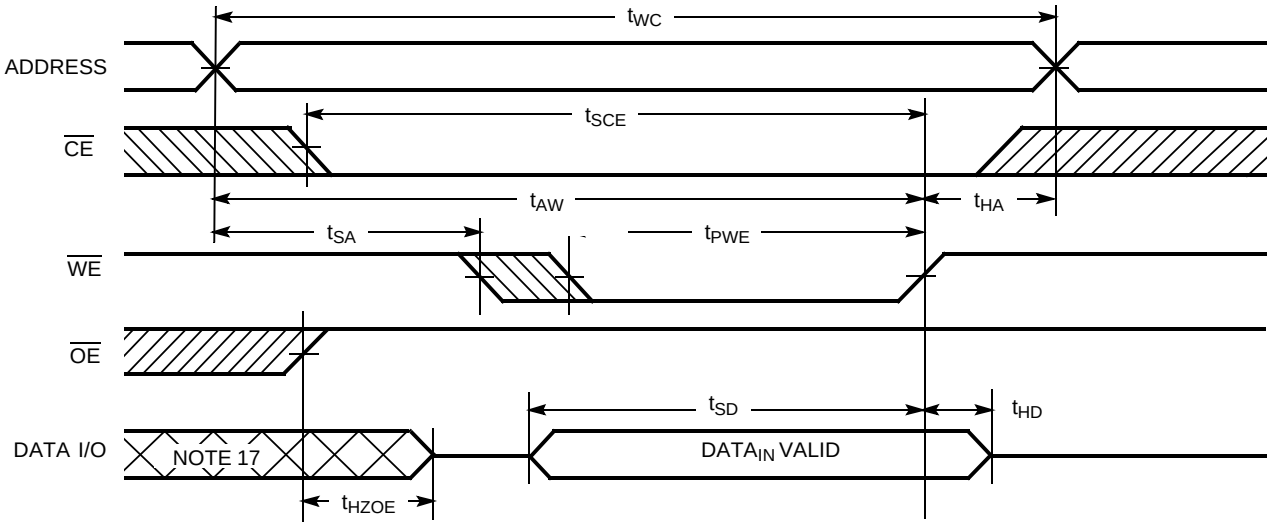
Read Cycle No. 2 ($\overline{OE}$ Controlled)[13, 14]



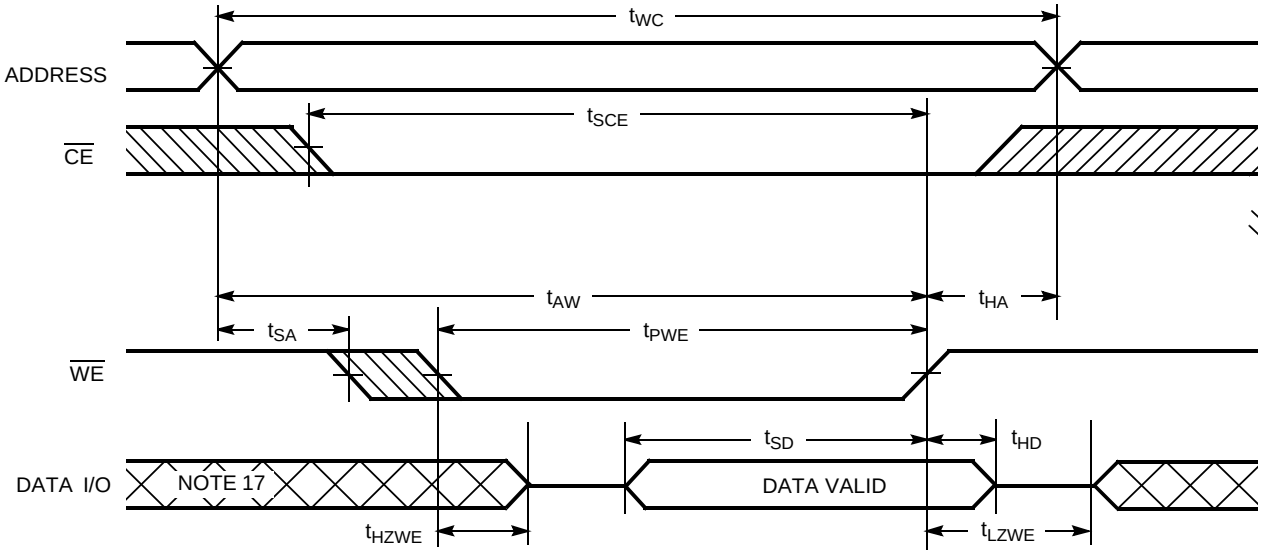
Notes:
12. Device is continuously selected. $\overline{OE}$, $\overline{CE}$ = V_{IL}.
13. $\overline{WE}$ is HIGH for read cycle.
14. Address valid prior to or coincident with $\overline{CE}$ transition LOW.

Switching Waveforms (continued)

Write Cycle No. 1(WE Controlled, OE HIGH During Write)[15, 16]



Write Cycle No. 2 (WE Controlled, OE LOW)[16]



Truth Table

CE	OE	WE	$I/O_0 – I/O_7$	Mode	Power
H	X	X	High Z	Power-Down	Standby (I_{SB})
L	L	H	Data Out	Read	Active (I_{CC})
L	X	L	Data In	Write	Active (I_{CC})
L	H	H	High Z	Selected, Outputs Disabled	Active (I_{CC})

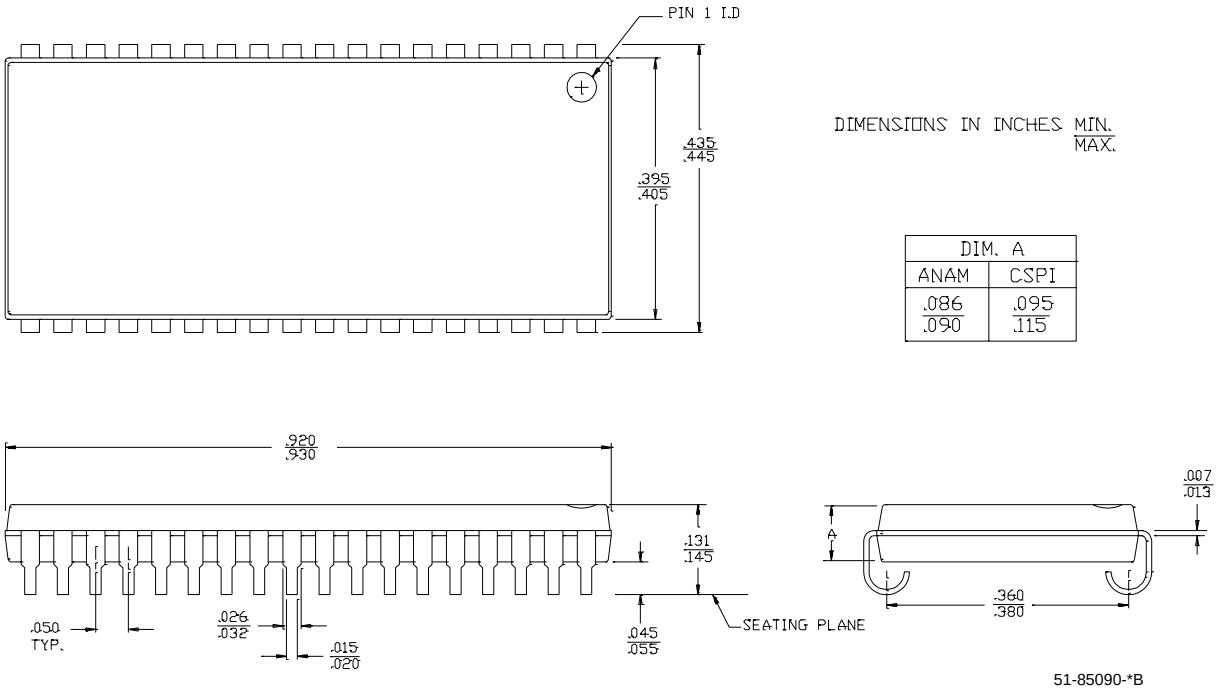
Notes:
15. Data I/O is high-impedance if $\overline{OE} = V_{IH}$.
16. If $\overline{CE}$ goes HIGH simultaneously with $\overline{WE}$ going HIGH, the output remains in a high-impedance state.
17. During this period the I/Os are in the output state and input signals should not be applied.

Ordering Information

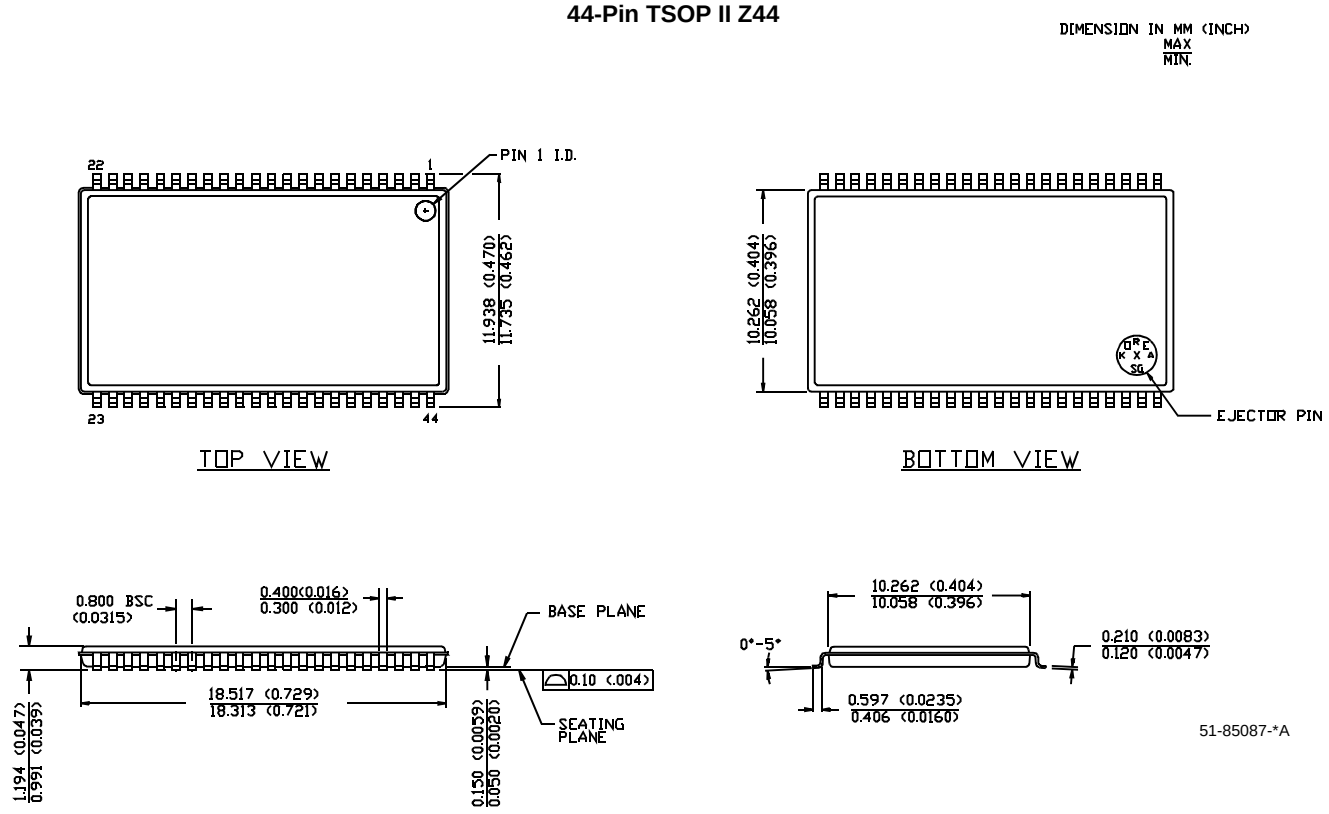
Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
12	CY7C1049BV33-12VC	V36	36-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1049BV33-12ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33L-12VC	V36	36-Lead (400-Mil) Molded SOJ	
	CY7C1049BV33-12VI	V36	36-Lead (400-Mil) Molded SOJ	Industrial
15	CY7C1049BV33-15VC	V36	36-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1049BV33L-15VC	V36	36-Lead (400-Mil) Molded SOJ	
	CY7C1049BV33-15ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33L-15ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33-15VI	V36	36-Lead (400-Mil) Molded SOJ	Industrial
	CY7C1049BV33-15ZI	Z44	44-Pin TSOP II Z44	
17	CY7C1049BV33-17VC	V36	36-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1049BV33L-17VC	V36	36-Lead (400-Mil) Molded SOJ	
	CY7C1049BV33-17ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33L-17ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33-17VI	V36	36-Lead (400-Mil) Molded SOJ	Industrial
	CY7C1049BV33L-17VI	V36	36-Lead (400-Mil) Molded SOJ	
	CY7C1049BV33-17ZI	Z44	44-Pin TSOP II Z44	
20	CY7C1049BV33-20VC	V36	36-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1049BV33L-20VC	V36	36-Lead (400-Mil) Molded SOJ	
	CY7C1049BV33-20ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33L-20ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33-20VI	V36	36-Lead (400-Mil) Molded SOJ	Industrial
	CY7C1049BV33-20ZI	Z44	44-Pin TSOP II Z44	
25	CY7C1049BV33-25VC	V36	36-Lead (400-Mil) Molded SOJ	Commercial
	CY7C1049BV33L-25VC	V36	36-Lead (400-Mil) Molded SOJ	
	CY7C1049BV33-25ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33L-25ZC	Z44	44-Pin TSOP II Z44	
	CY7C1049BV33-25VI	v36	36-Lead (400-Mil) Molded SOJ	Industrial

Package Diagrams

36-Lead (400-Mil) Molded SOJ V36



44-Pin TSOP II Z44



Document History Page

Document Title: CY7C1049BV33 512K x 8 Static RAM Document Number: 38-05139				
REV.	**ECN NO.**	**Issue Date**	**Orig. of Change**	**Description of Change**
**	113091	02/13/02	DSG	Change from Spec number: 38-00931 to 38-05139
*A	116475	09/16/02	CEA	Add applications foot note to data sheet, page 1